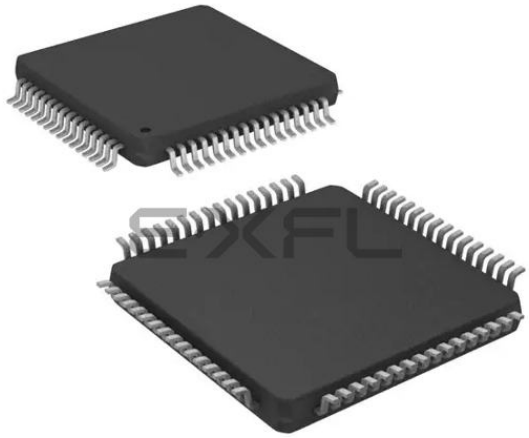


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

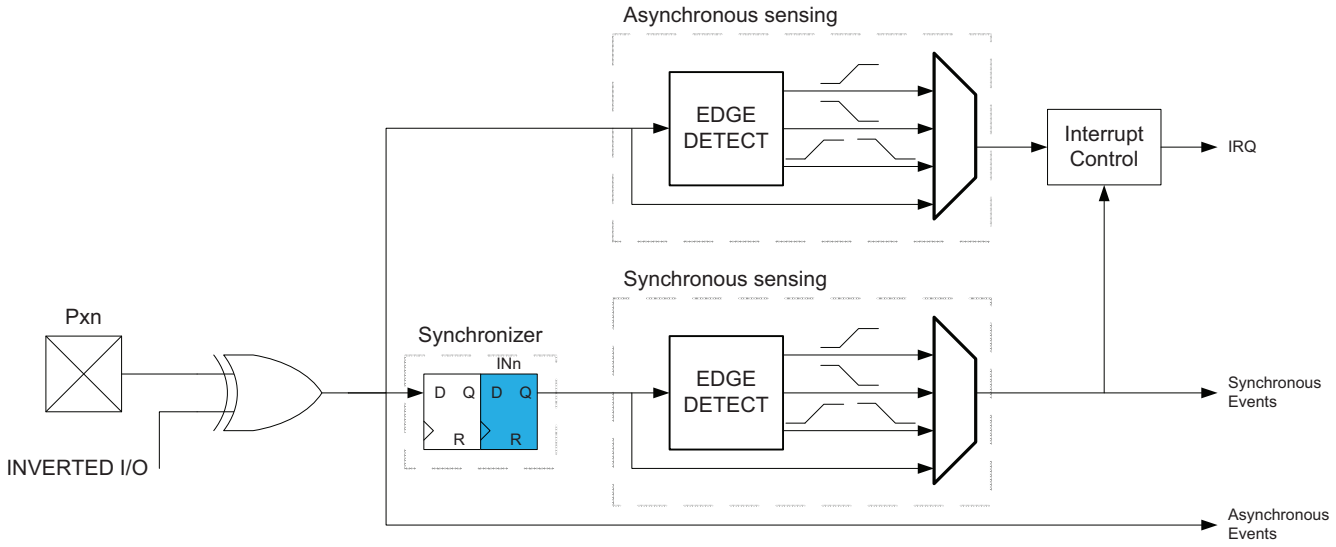
Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	AVR
Core Size	8/16-Bit
Speed	32MHz
Connectivity	I²C, IrDA, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	50
Program Memory Size	128KB (64K x 16)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-TQFP
Supplier Device Package	64-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/atxmega128d3-aur

14.4 Input Sensing

Input sensing is synchronous or asynchronous depending on the enabled clock for the ports, and the configuration is shown in Figure 14-7.

Figure 14-7. Input Sensing System Overview

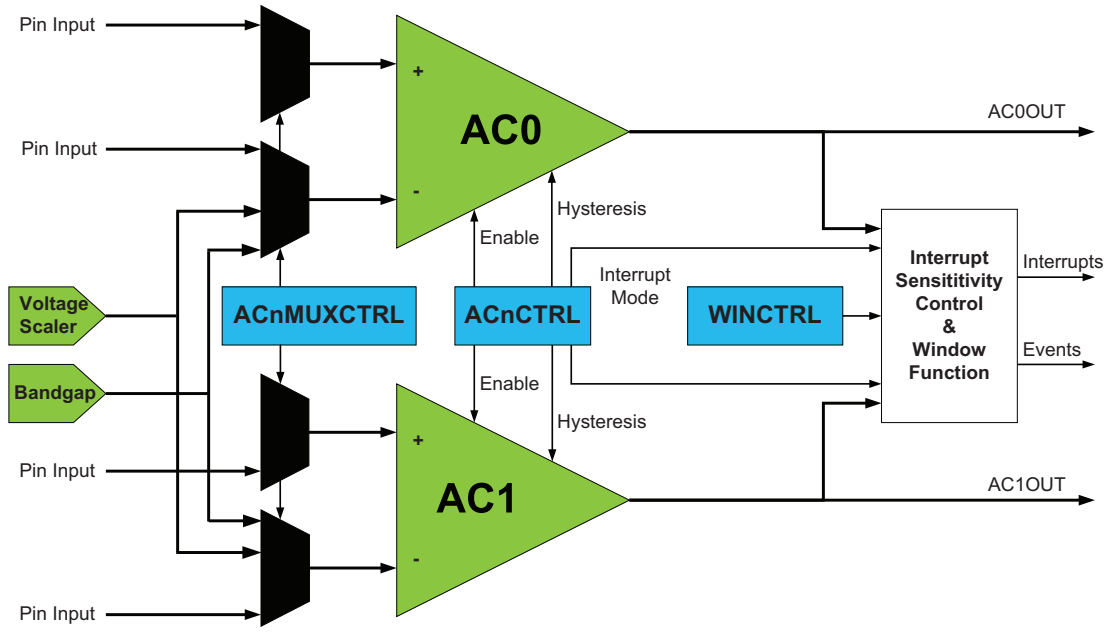


When a pin is configured with inverted I/O, the pin value is inverted before the input sensing.

14.5 Alternate Port Functions

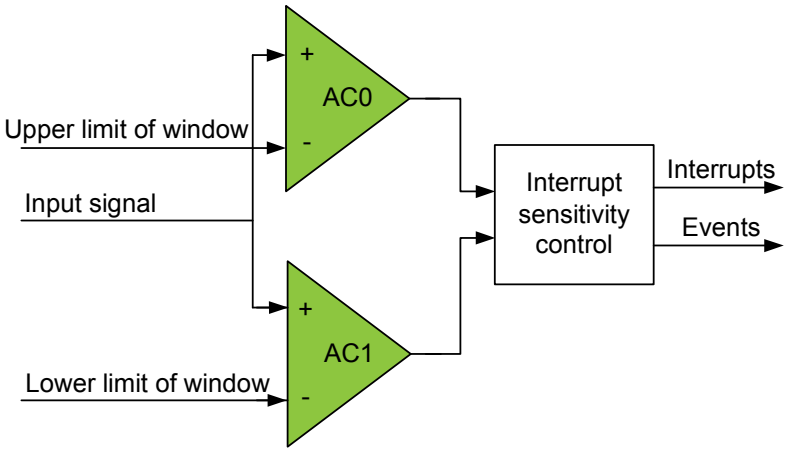
Most port pins have alternate pin functions in addition to being a general purpose I/O pin. When an alternate function is enabled, it might override the normal port pin function or pin value. This happens when other peripherals that require pins are enabled or configured to use pins. If and how a peripheral will override and use pins is described in the section for that peripheral. “Pinout and Pin Functions” on page 50 shows which modules on peripherals that enable alternate functions on a pin, and which alternate functions that are available on a pin.

Figure 26-1. Analog Comparator Overview



The window function is realized by connecting the external inputs of the two analog comparators in a pair as shown in Figure 26-2.

Figure 26-2. Analog Comparator Window Function



32.1.8 Bandgap and Internal 1.0V Reference Characteristics

Table 32-13. Bandgp and Internal 1.0V Reference Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Startup time	As reference for ADC		1 Clk_{PER} + 2.5µs		µs
		As input voltage to ADC and AC		1.5		
	Bandgap voltage			1.1		V
INT1V	Internal 1.00V reference	T = 85°C, after calibration	0.99	1	1.01	
	Variation over voltage and temperature	Calibrated at T = 85°C		1		%

32.1.9 Brownout Detection Characteristics

Table 32-14. Brownout Detection Characteristics (1)

Symbol	Parameter (BOD level 0 at 85°C)	Condition	Min.	Typ.	Max.	Units
V_{BOT}	BOD level 0 falling V_{CC}		1.40	1.60	1.70	V
	BOD level 1 falling V_{CC}			1.8		
	BOD level 2 falling V_{CC}			2.0		
	BOD level 3 falling V_{CC}			2.2		
	BOD level 4 falling V_{CC}			2.4		
	BOD level 5 falling V_{CC}			2.6		
	BOD level 6 falling V_{CC}			2.8		
	BOD level 7 falling V_{CC}			3.0		
t_{BOD}	Detection time	Continuous mode		0.4		µs
		Sampled mode		1000		
V_{HYST}	Hysteresis			1.0		%

Note: 1. BOD is calibrated at 85°C within BOD level 0 values, and BOD level 0 is the default level.

32.1.10 External Reset Characteristics

Table 32-15. External Reset Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
t_{EXT}	Minimum reset pulse width		1000	90		ns
V_{RST}	Reset threshold voltage	V_{CC} = 2.7 - 3.6V		0.45 * V_{CC}		V
		V_{CC} = 1.6 - 2.7V		0.42 * V_{CC}		
R_{RST}	Reset pin pull-up resistor			25		kΩ

32.2.3 Current Consumption

Table 32-33. Current Consumption for Active Mode and Sleep Modes

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{CC}	Active power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		50		µA
			V_{CC} = 3.0V		130		
		1MHz, Ext. Clk	V_{CC} = 1.8V		215		
			V_{CC} = 3.0V		475		
		2MHz, Ext. Clk	V_{CC} = 1.8V		445	600	
			V_{CC} = 3.0V		0.95	1.5	mA
		32MHz, Ext. Clk			7.8	12.0	
	Idle power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		2.8		µA
			V_{CC} = 3.0V		3		
		1MHz, Ext. Clk	V_{CC} = 1.8V		46		
			V_{CC} = 3.0V		92		
		2MHz, Ext. Clk	V_{CC} = 1.8V		93	225	
			V_{CC} = 3.0V		184	350	
		32MHz, Ext. Clk			2.9	5.0	mA
	Power-down power consumption	T = 25°C	V_{CC} = 3.0V		0.07	1.0	µA
		T = 85°C			1.3	5.0	
		T = 105°C			4.0	8.0	
		WDT and sampled BOD enabled, T = 25°C	V_{CC} = 3.0V		1.3	2.0	
		WDT and sampled BOD enabled, T = 85°C			2.6	6.0	
		WDT and sampled BOD enabled, T= 105°C			5.0	10	
	Power-save power consumption (2)	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V_{CC} = 1.8V		1.7		
			V_{CC} = 3.0V		1.8		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.5	2.0	
			V_{CC} = 3.0V		0.7	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.9	3.0	
			V_{CC} = 3.0V		1.2	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin substracted	V_{CC} = 3.0V		120		

Notes: 1. All Power Reduction Registers set.
2. Maximum limits are based on characterization, and not tested in production.

Table 32-58. Two-wire Interface Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{IH}	Input high voltage		$0.7V_{CC}$		V_{CC} + 0.5	V
V_{IL}	Input low voltage		-0.5		$0.3V_{CC}$	
V_{hys}	Hysteresis of Schmitt trigger inputs		$0.05V_{CC}$ (1)			
V_{OL}	Output low voltage	3mA, sink current	0		0.4	
t_r	Rise time for both SDA and SCL		$20 + 0.1C_b$ (1)(2)		300	ns
t_{of}	Output fall time from V_{IHmin} to V_{ILmax}	10pF < C_b < 400pF (2)	$20 + 0.1C_b$ (1)(2)		250	
t_{SP}	Spikes suppressed by input filter		0		50	
I_I	Input current for each I/O pin	$0.1V_{CC} < V_I < 0.9V_{CC}$	-10		10	µA
C_I	Capacitance for each I/O pin				10	pF
f_{SCL}	SCL clock frequency	f_{PER} (3) > max(10f_{SCL}, 250kHz)	0		400	kHz
R_P	Value of pull-up resistor	$f_{SCL} \leq$ 100kHz	$\frac{V_{CC}-0.4V}{3mA}$		$\frac{100ns}{C_b}$	Ω
		f_{SCL} > 100kHz			$\frac{300ns}{C_b}$	
$t_{HD;STA}$	Hold time (repeated) START condition	$f_{SCL} \leq$ 100kHz	4.0			µs
		f_{SCL} > 100kHz	0.6			
t_{LOW}	Low period of SCL clock	$f_{SCL} \leq$ 100kHz	4.7			
		f_{SCL} > 100kHz	1.3			
t_{HIGH}	High period of SCL clock	$f_{SCL} \leq$ 100kHz	4.0			
		f_{SCL} > 100kHz	0.6			
$t_{SU;STA}$	Set-up time for a repeated START condition	$f_{SCL} \leq$ 100kHz	4.7			
		f_{SCL} > 100kHz	0.6			
$t_{HD;DAT}$	Data hold time	$f_{SCL} \leq$ 100kHz	0		3.45	µs
		f_{SCL} > 100kHz	0		0.9	
$t_{SU;DAT}$	Data setup time	$f_{SCL} \leq$ 100kHz	250			
		f_{SCL} > 100kHz	100			
$t_{SU;STO}$	Setup time for STOP condition	$f_{SCL} \leq$ 100kHz	4.0			
		f_{SCL} > 100kHz	0.6			
t_{BUF}	Bus free time between a STOP and START condition	$f_{SCL} \leq$ 100kHz	4.7			
		f_{SCL} > 100kHz	1.3			

Notes:
1. Required only for f_{SCL} > 100kHz.
2. C_b = Capacitance of one bus line in pF.
3. f_{PER} = Peripheral clock frequency.

32.4.3 Current Consumption

Table 32-91. Current Consumption for Active Mode and Sleep Modes

Symbol	Parameter	Condition		Min.	Typ.	Max.	Units
I_{CC}	Active power consumption (1)	32kHz, Ext. Clk	V_{CC} = 1.8V		60		µA
			V_{CC} = 3.0V		140		
		1MHz, Ext. Clk	V_{CC} = 1.8V		245		
			V_{CC} = 3.0V		550		
		2MHz, Ext. Clk	V_{CC} = 1.8V		440	700	
			V_{CC} = 3.0V		0.9	1.5	mA
		32MHz, Ext. Clk			9.0	15	
	Idle power consumption (2)	32kHz, Ext. Clk	V_{CC} = 1.8V		3.0		µA
			V_{CC} = 3.0V		3.5		
		1MHz, Ext. Clk	V_{CC} = 1.8V		55		
			V_{CC} = 3.0V		110		
		2MHz, Ext. Clk	V_{CC} = 1.8V		105	350	
			V_{CC} = 3.0V		215	650	
		32MHz, Ext. Clk			3.4	8.0	mA
	Power-down power consumption	T = 25°C	V_{CC} = 3.0V		0.1	1.0	µA
		T = 85°C			3.5	6.0	
		T = 105°C			10	15	
		WDT and sampled BOD enabled, T = 25°C	V_{CC} = 3.0V		1.5	2.0	
		WDT and sampled BOD enabled, T = 85°C			5.8	10	
		WDT and sampled BOD enabled, T= 105°C			12	20	
	Power-save power consumption (3)	RTC from ULP clock, WDT and sampled BOD enabled, T = 25°C	V_{CC} = 1.8V		1.3		
			V_{CC} = 3.0V		1.4		
		RTC from 1.024kHz low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.7	2.0	
			V_{CC} = 3.0V		0.8	2.0	
		RTC from low power 32.768kHz TOSC, T = 25°C	V_{CC} = 1.8V		0.9	3.0	
			V_{CC} = 3.0V		1.1	3.0	
	Reset power consumption	Current through $\overline{\text{RESET}}$ pin substracted	V_{CC} = 3.0V		170		

Notes:
1. All power reduction registers set including FPRM and EPRM.
2. All power reduction registers set without FPRM and EPRM.
3. Maximum limits are based on characterization, and not tested in production.

32.4.13 Clock and Oscillator Characteristics

32.4.13.1 Calibrated 32.768kHz Internal Oscillator Characteristics

Table 32-106. 32.768kHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency			32.768		kHz
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-0.5		0.5	%
	User calibration accuracy		-0.5		0.5	

32.4.13.2 Calibrated 2MHz RC Internal Oscillator Characteristics

Table 32-107. 2MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	1.8	2.0	2.2	MHz
	Factory calibrated frequency			2.0		
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration stepsize			0.18		

32.4.13.3 Calibrated 32MHz Internal Oscillator Characteristics

Table 32-108. 32MHz Internal Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Frequency range	DFLL can tune to this frequency over voltage and temperature	30	32	55	MHz
	Factory calibrated frequency			32		
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-1.5		1.5	%
	User calibration accuracy		-0.2		0.2	
	DFLL calibration step size			0.19		

32.4.13.4 32kHz Internal ULP Oscillator Characteristics

Table 32-109. 32kHz Internal ULP Oscillator Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
	Factory calibrated frequency			32		kHz
	Factory calibration accuracy	T = 85°C, V_{CC} = 3.0V	-12		12	%
	Accuracy		-30		30	

32.5 Atmel ATxmega256D3

32.5.1 Absolute Maximum Ratings

Stresses beyond those listed in Table 32-117 may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Table 32-117. Absolute Maximum Ratings

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		-0.3		4	V
I_{VCC}	Current into a V_{CC} pin				200	mA
I_{GND}	Current out of a Gnd pin				200	
V_{PIN}	Pin voltage with respect to Gnd and V_{CC}		-0.5		V_{CC} + 0.5	V
I_{PIN}	I/O pin sink/source current		-25		25	mA
T_A	Storage temperature		-65		150	°C
T_j	Junction temperature				150	

32.5.2 General Operating Ratings

The device must operate within the ratings listed in Table 32-118 in order for all other electrical characteristics and typical characteristics of the device to be valid.

Table 32-118. General Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{CC}	Power supply voltage		1.60		3.6	V
AV_{CC}	Analog supply voltage		1.60		3.6	
T_A	Temperature range		-40		85	°C
T_j	Junction temperature		-40		105	

Table 32-119. Operating Voltage and Frequency

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk_{CPU}	CPU clock frequency	V_{CC} = 1.6V	0		12	MHz
		V_{CC} = 1.8V	0		12	
		V_{CC} = 2.7V	0		32	
		V_{CC} = 3.6V	0		32	

The maximum CPU clock frequency depends on V_{CC}. As shown in Figure 32-29 on page 140 the frequency vs. V_{CC} curve is linear between 1.8V < V_{CC} < 2.7V.

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
V_{in}	Input range		0		V_{REF}	V
	Conversion range	Differential mode, Vinp - Vinn	$-V_{REF}$		V_{REF}	
	Conversion range	Single ended unsigned mode, Vinp	$-\Delta V$		$V_{REF} - \Delta V$	
ΔV	Fixed offset voltage			200		lsb

Table 32-154. Clock and Timing

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Clk_{ADC}	ADC clock frequency	Maximum is 1/4 of peripheral clock frequency	100		1800	kHz
		Measuring internal signals	100		125	
f_{ClkADC}	Sample rate		16		300	ksps
f_{ADC}	Sample rate	Current limitation (CURRLIMIT) off	16		300	
		CURRLIMIT = LOW	16		250	
		CURRLIMIT = MEDIUM	16		150	
		CURRLIMIT = HIGH	16		50	
	Sampling time	Configurable in steps of 1/2 Clk_{ADC} cycles up to 32 Clk_{ADC} cycles	0.28		320	µs
	Conversion time (latency)	(RES+1)/2 + GAIN RES (Resolution) = 8 or 12, GAIN = 0 to 3	5.5		10	Clk_{ADC} cycles
	Start-up time	ADC clock cycles		12	24	
	ADC settling time	After changing reference or input mode		7	7	

Figure 33-33. INL Error vs. Input Code

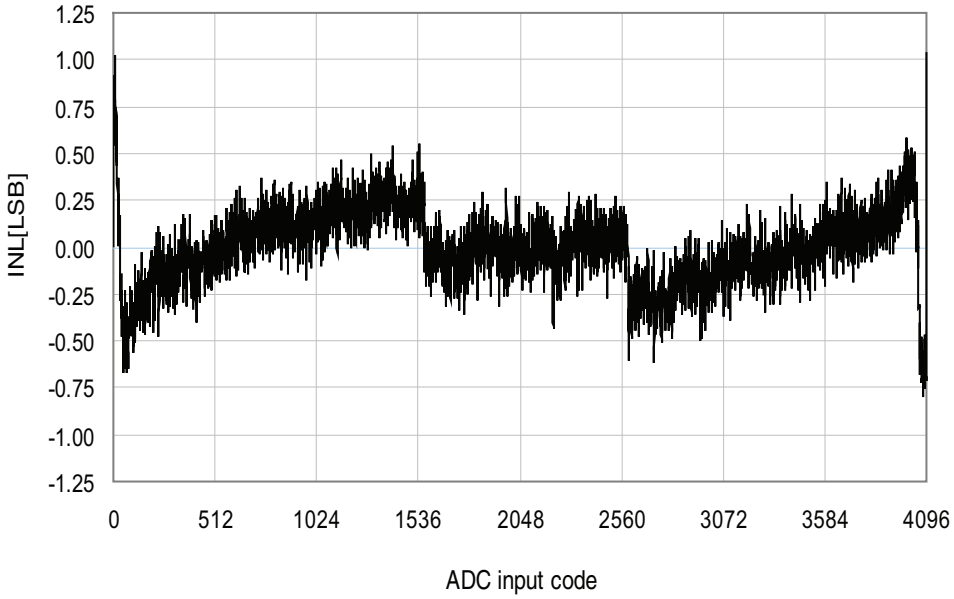


Figure 33-34. DNL Error vs. External V_{REF}

T = 25°C, V_{CC} = 3.6V, external reference

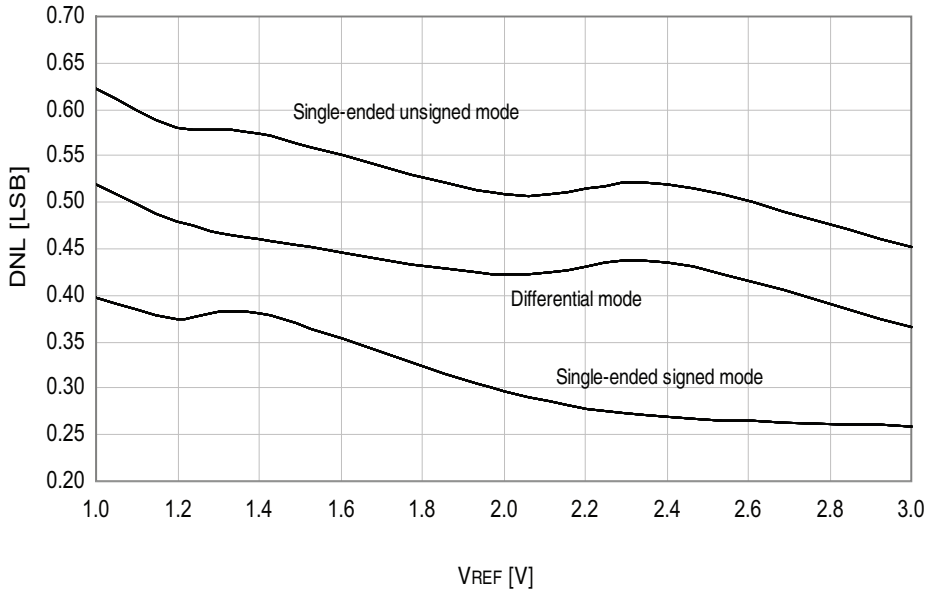
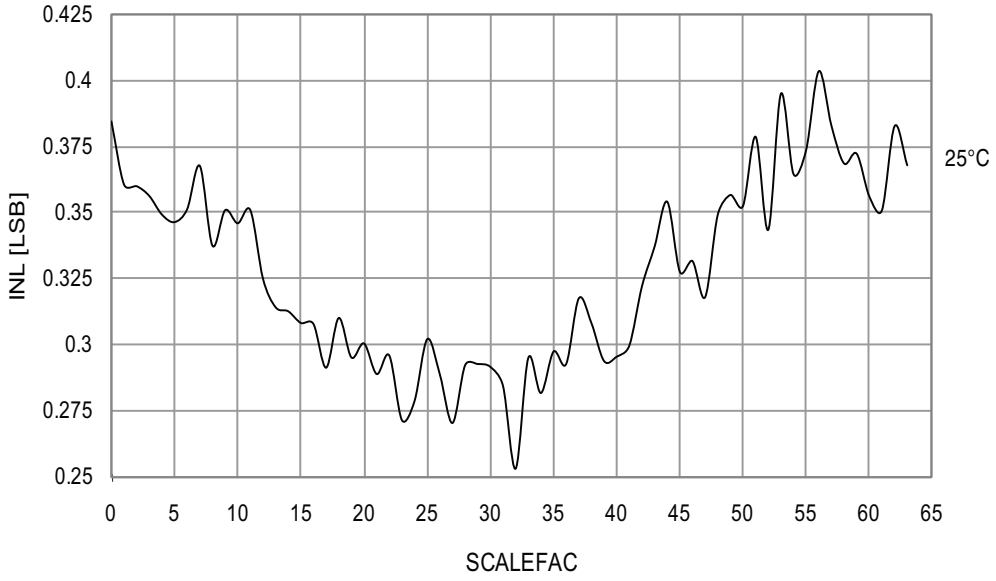


Figure 33-45. Voltage Scaler INL vs. SCALEFAC

T = 25°C, V_{CC} = 3.0V



33.1.5 Internal 1.0V Reference Characteristics

Figure 33-46. ADC Internal 1.0V Reference vs. Temperature

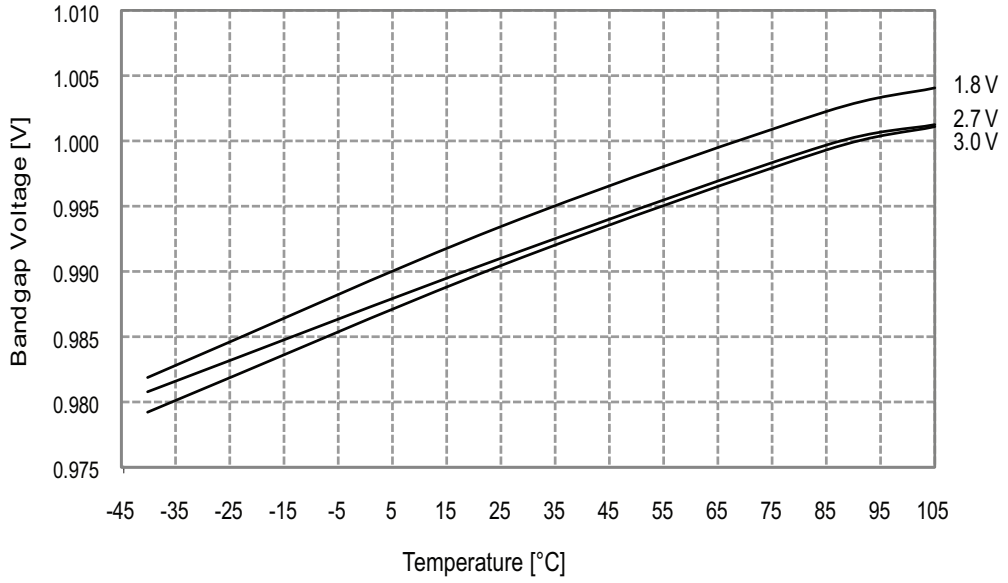


Figure 33-63. 32MHz Internal Oscillator CALA Calibration Step Size

T = 25°C, V_{CC} = 3.0V

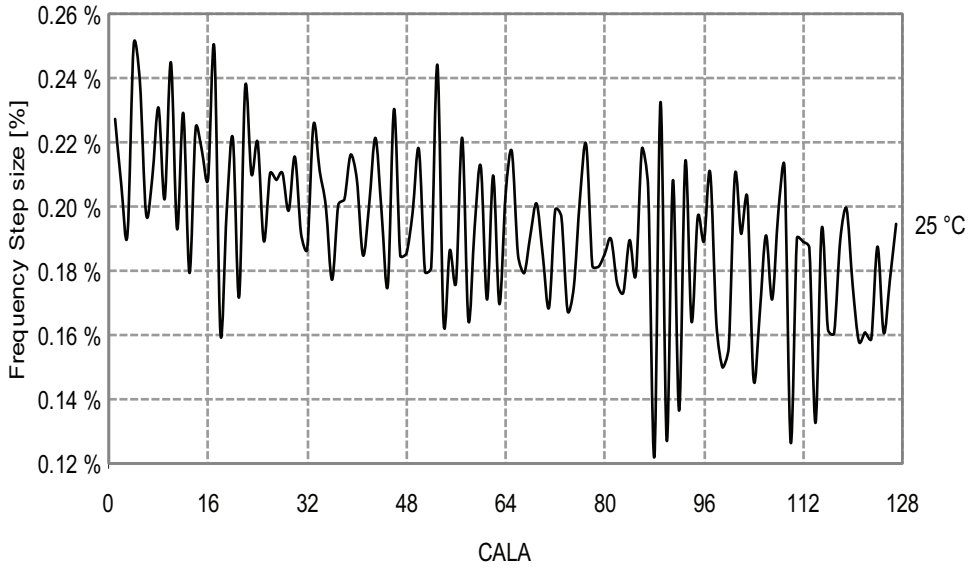


Figure 33-64. 32MHz Internal Oscillator CALA Calibration Step Size

T = 85°C, V_{CC} = 3.0V

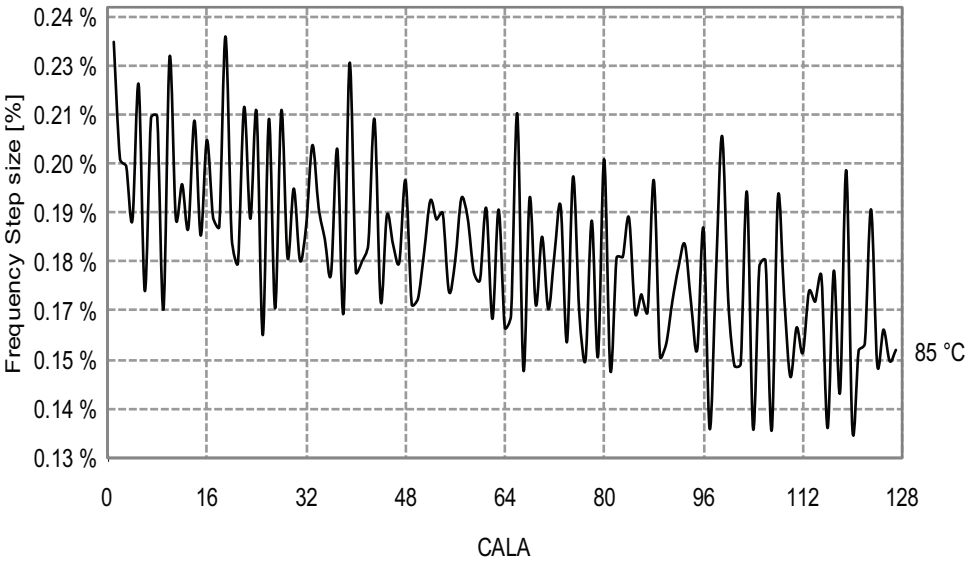


Figure 33-76. Active Mode Supply Current vs. V_{CC}

f_{SYS} = 2MHz internal oscillator

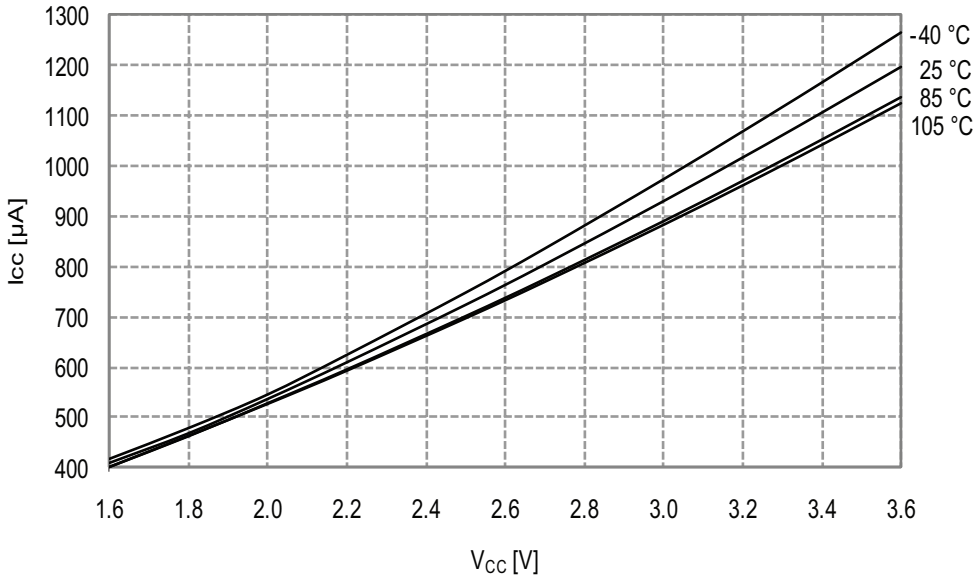
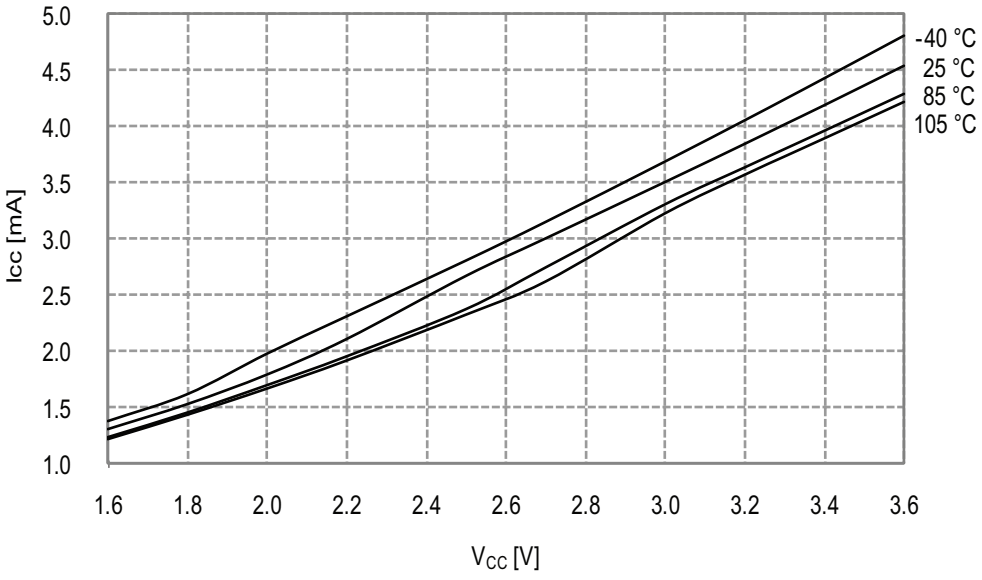


Figure 33-77. Active Mode Supply Current vs. V_{CC}

f_{SYS} = 32MHz internal oscillator prescaled to 8MHz



33.3.8.4 32MHz Internal Oscillator

Figure 33-201. 32MHz Internal Oscillator Frequency vs. Temperature

DFLL disabled

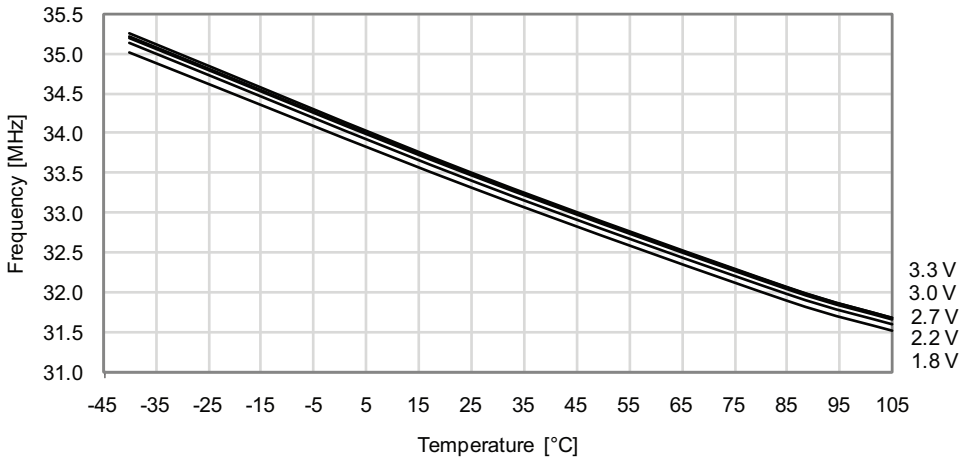


Figure 33-202. 32MHz Internal Oscillator Frequency vs. Temperature

DFLL enabled, from the 32.768kHz internal oscillator

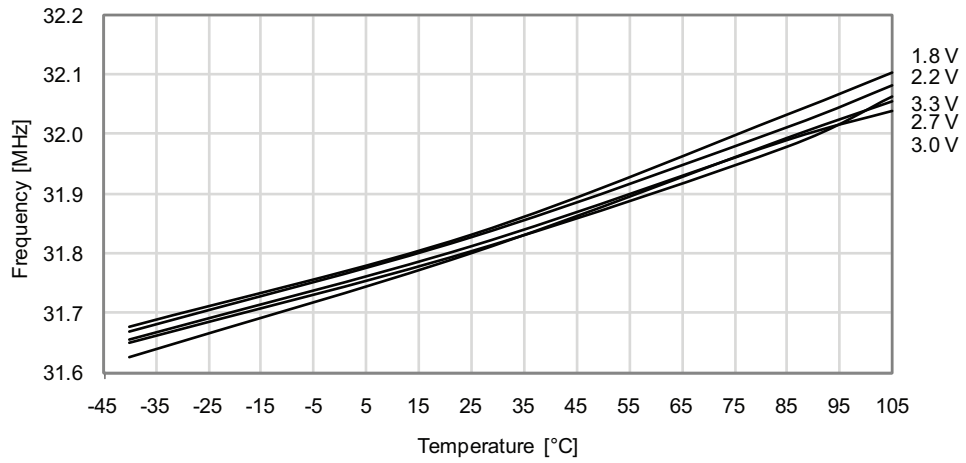


Figure 33-203. 32MHz Internal Oscillator CALA Calibration Step Size

T = -40°C, V_{CC} = 3.0V

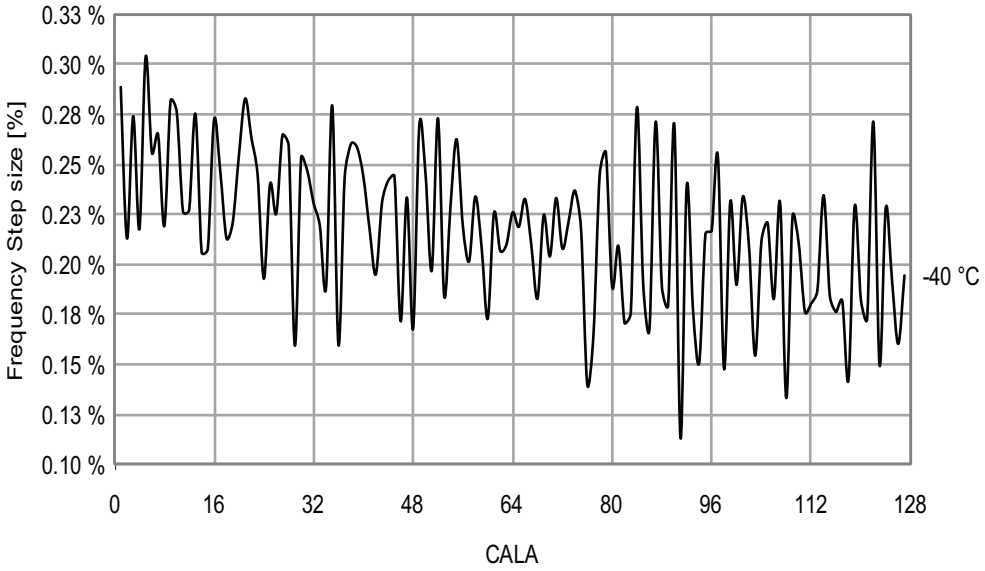


Figure 33-204. 32MHz Internal Oscillator CALA Calibration Step Size

T = 25°C, V_{CC} = 3.0V

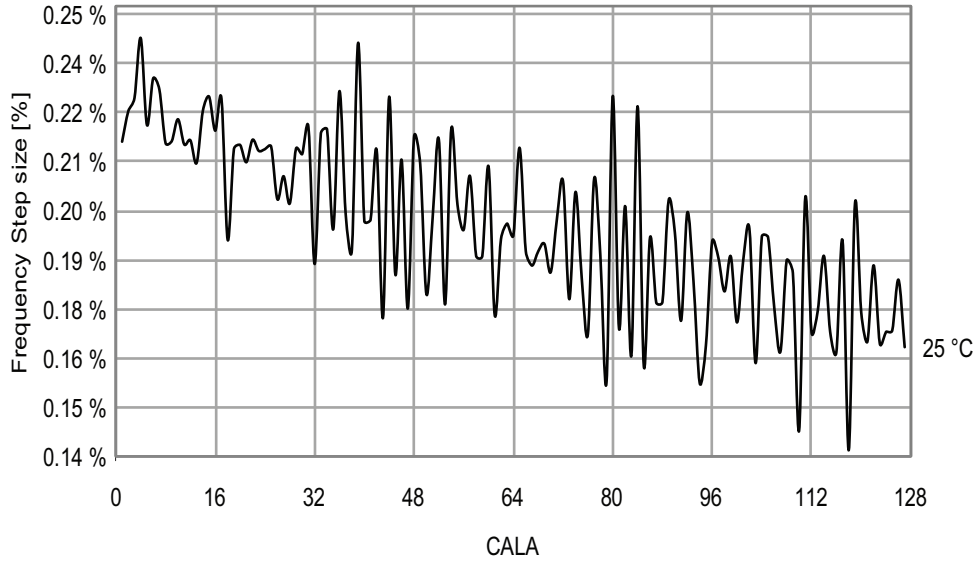


Figure 33-275. 32MHz Internal Oscillator CALA Calibration Step Size

T = 85°C, V_{CC} = 3.0V

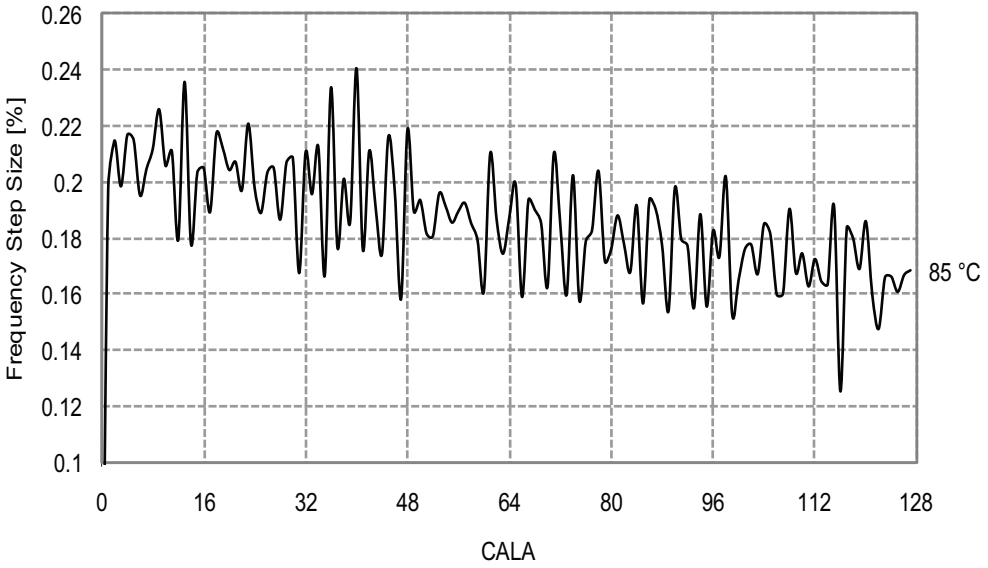


Figure 33-276. 32MHz Internal Oscillator CALA Calibration Step Size

T = 105°C, V_{CC} = 3.0V

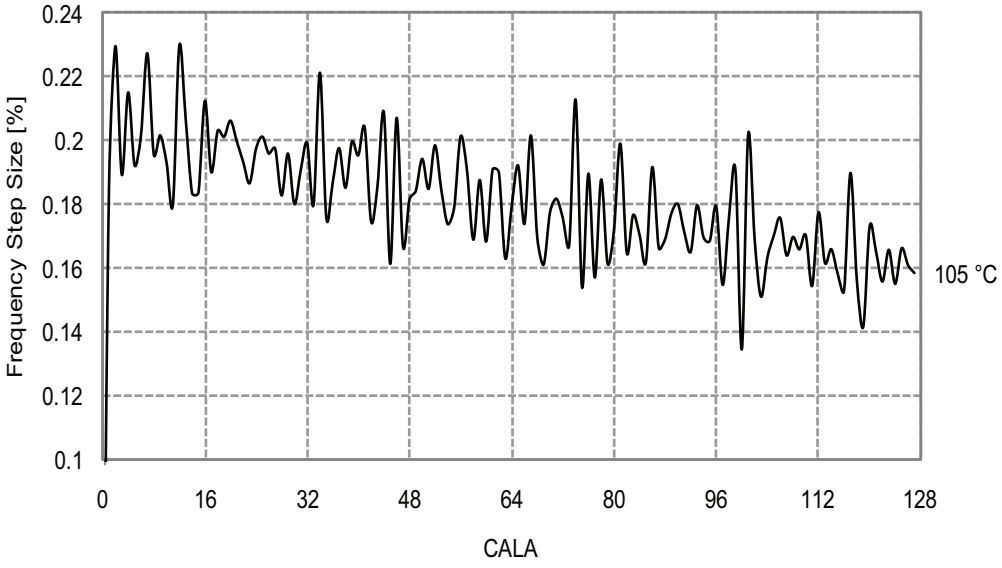
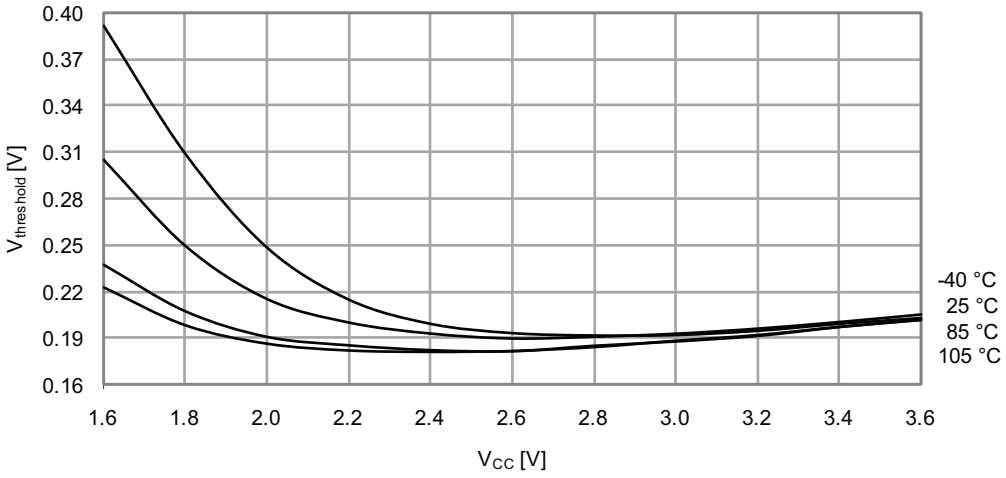


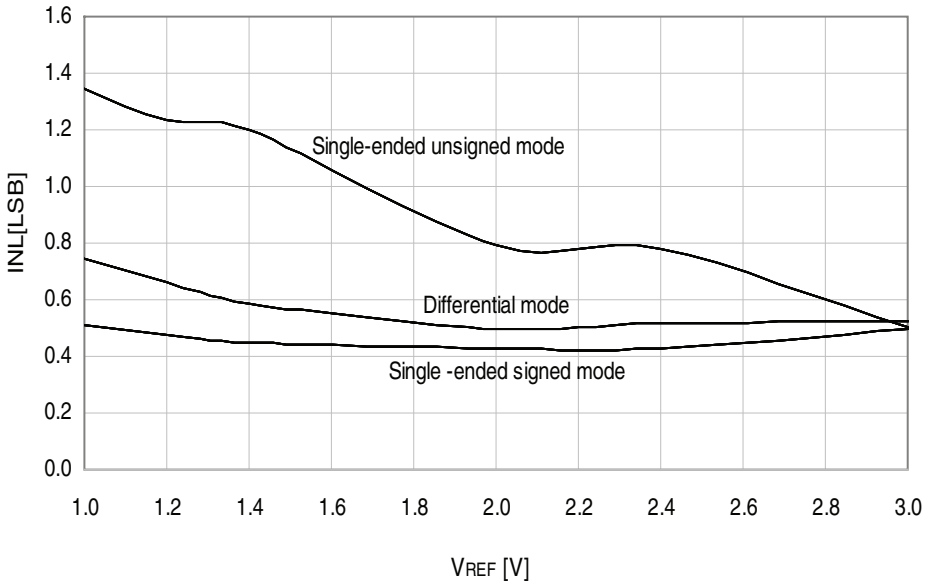
Figure 33-381.I/O Pin Input Hysteresis vs. V_{CC}



33.6.3 ADC Characteristics

Figure 33-382. INL Error vs. External V_{REF}

T = 25°C, V_{CC} = 3.6V, external reference



33.6.8.5 32MHz Internal Oscillator Calibrated to 48MHz

Figure 33-415. 48MHz Internal Oscillator Frequency vs. Temperature

DFLL disabled

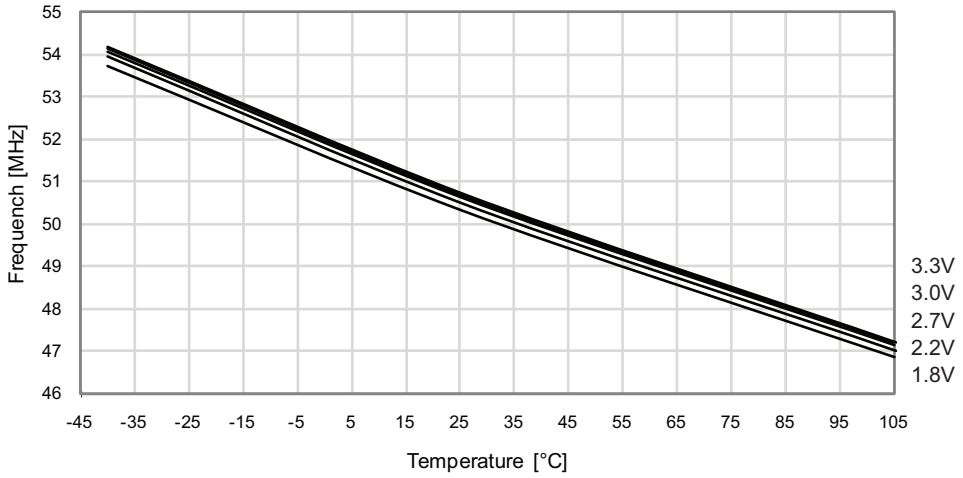
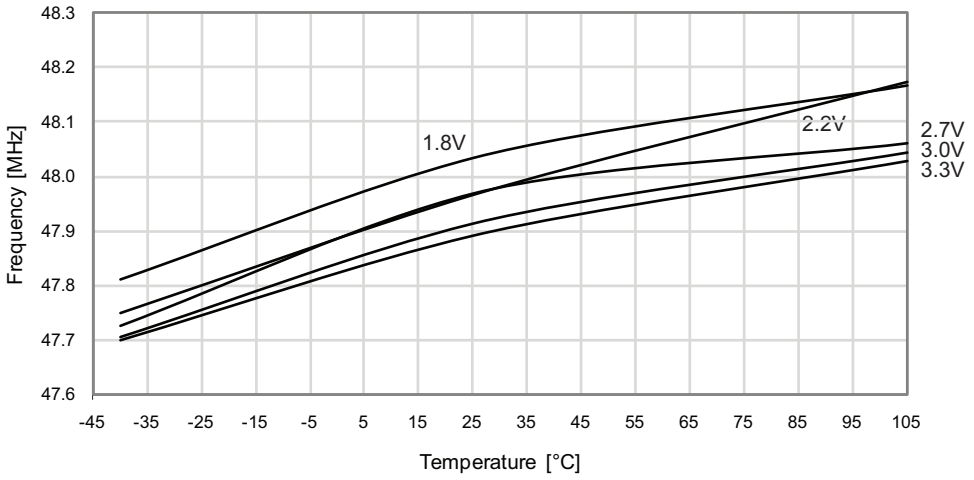


Figure 33-416. 48MHz Internal Oscillator Frequency vs. Temperature

DFLL enabled, from the 32.768kHz internal oscillator



34.4.8 Rev. B

- Bandgap voltage input for the ACs can not be changed when used for both ACs simultaneously
- VCC voltage scaler for AC is non-linear
- ADC gain stage cannot be used for single conversion
- ADC has increased INL error for some operating conditions
- ADC gain stage output range is limited to 2.4V
- ADC Event on compare match non-functional
- ADC propagation delay is not correct when 8× – 64× gain is used
- Bandgap measurement with the ADC is non-functional when VCC is below 2.7V
- Accuracy lost on first three samples after switching input to ADC gain stage
- Configuration of PGM and CWCM not as described in the XMEGA D Manual
- PWM is not restarted properly after a fault in cycle-by-cycle mode
- BOD will be enabled at any reset
- EEPROM page buffer always written when NVM DATA0 is written
- Pending full asynchronous pin change interrupts will not wake the device
- Pin configuration does not affect Analog Comparator Output
- NMI Flag for Crystal Oscillator Failure automatically cleared
- Writing EEPROM or Flash while reading any of them will not work
- RTC Counter value not correctly read after sleep
- Pending asynchronous RTC-interrupts will not wake up device
- TWI Transmit collision flag not cleared on repeated start
- Clearing TWI Stop Interrupt Flag may lock the bus
- TWI START condition at bus timeout will cause transaction to be dropped
- TWI Data Interrupt Flag (DIF) erroneously read as set
- WDR instruction inside closed window will not issue reset
- Non available functions and options
- Sampled BOD in Active mode will cause noise when bandgap is used as reference
- Temperature sensor not calibrated

1. Bandgap voltage input for the ACs cannot be changed when used for both ACs simultaneously

If the Bandgap voltage is selected as input for one Analog Comparator (AC) and then selected/deselected as input for another AC, the first comparator will be affected for up to 1µs and could potentially give a wrong comparison result.

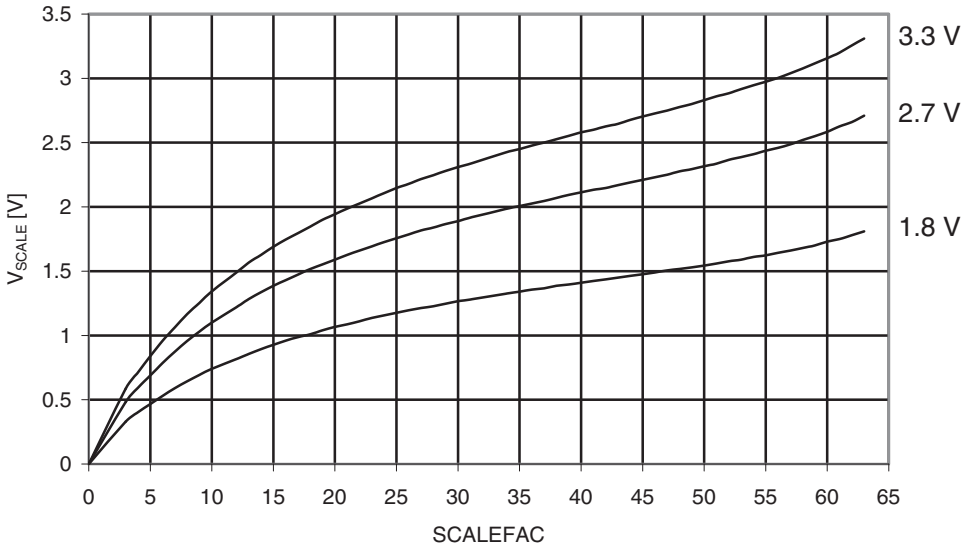
Problem fix/workaround

If the Bandgap is required for both ACs simultaneously, configure the input selection for both ACs before enabling any of them.

2. VCC voltage scaler for AC is non-linear

The 6-bit VCC voltage scaler in the Analog Comparators is non-linear.

Figure 34-7. Analog Comparator Voltage Scaler vs. Scalefac
T = 25°C



Problem fix/workaround

Use external voltage input for the analog comparator if accurate voltage levels are needed.

3. ADC gain stage cannot be used for single conversion

The ADC gain stage will not output correct result for single conversion that is triggered and started from software or event system.

Problem fix/workaround

When the gain stage is used, the ADC must be set in free running mode for correct results.

4. ADC has increased INL error for some operating conditions

Some ADC configurations or operating condition will result in increased INL error.

In signed mode INL is increased to:

6LSB for sample rates above 130ksps, and up to 8LSB for 200ksps sample rate.

6LSB for reference voltage below 1.1V when V_{CC} is above 3.0V.

20LSB for ambient temperature below 0°C and reference voltage below 1.3V.

In unsigned mode, the INL error cannot be guaranteed, and this mode should not be used.

Problem fix/workaround

None, avoid using the ADC in the above configurations in order to prevent increased INL error. Use the ADC in signed mode also for single ended measurements.

5. ADC gain stage output range is limited to 2.4V

The amplified output of the ADC gain stage will never go above 2.4V, hence the differential input will only give correct output when below 2.4V/gain. For the available gain settings, this gives a differential input range of: